

<p>Substitute for form 1449/PTO</p> <p>NOV 09 2007</p> <p>U.S. PATENT &amp; TRADEMARK OFFICE</p> <p>INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)</p>				<b>Complete if Known</b>	
				Application No.:	10/549,863
				Filing Date:	December 8, 2006
				First Named Inventor:	Nigel P. Smith
				Art Unit:	2823
				Examiner Name:	William D. Coleman
Sheet	1	of	1	Attorney Docket No.:	NAN154 US 8026

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Examiner Signature:	/W. David Coleman/	Date Considered:	05/23/2008
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\* Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication with applicant.